

30V N-Channel Enhancement Mode MOSFET

Description

The AP3404CI uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

$V_{DS} = 30V$ $I_D = 5.2A$

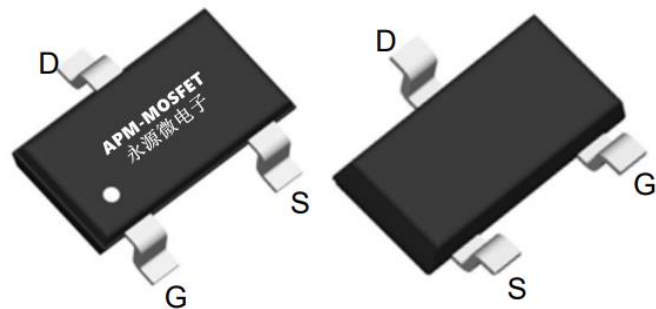
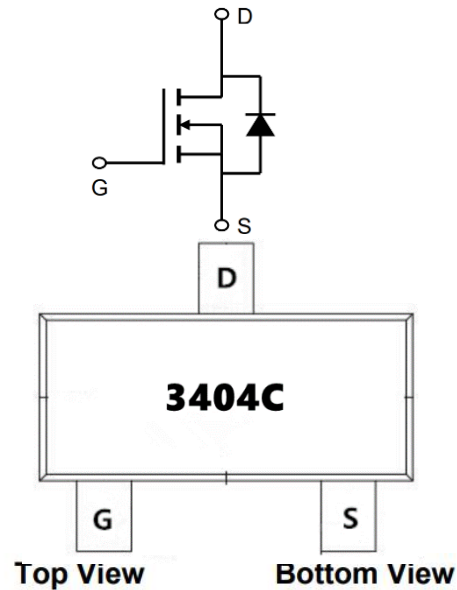
$R_{DS(ON)} < 38m\Omega$ @ $V_{GS}=10V$ (Type: 29m Ω)

Application

Lithium battery protection

Wireless impact

Mobile phone fast charging



Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP3404CI	SOT23L	3404C	3000

Absolute Maximum Ratings ($T_C=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	30	V
V_{GS}	Gate-Source Voltage	± 20	V
$I_D@T_A=25^\circ\text{C}$	Continuous Drain Current	5.2	A
$I_D@T_A=70^\circ\text{C}$	Continuous Drain Current	3.5	A
IDM	Pulsed Drain Current ²	18	A
$P_D@T_A=25^\circ\text{C}$	Total Power Dissipation ³	1.25	W
TSTG	Storage Temperature Range	-55 to 150	$^\circ\text{C}$
T_J	Operating Junction Temperature Range	-55 to 150	$^\circ\text{C}$
$R_{\theta JA}$	Thermal Resistance Junction-ambient ¹	125	$^\circ\text{C}/\text{W}$
$R_{\theta JA}$	Thermal Resistance Junction-Ambient ¹	85	$^\circ\text{C}/\text{W}$

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Electrical Characteristics ($T_c=25^{\circ}\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
V(BR)DSS	Drain-Source Breakdown Voltage	$I_D = 250\text{mA}$, $V_{GS} = 0\text{V}$	30	-	-	V
IDSS	Zero Gate Voltage Drain Current	$V_{DS} = 30\text{V}$, $V_{GS} = 0\text{V}$	-	-	1.0	mA
IGSS	Gate-Body Leakage Current	$V_{DS} = 0\text{V}$, $V_{GS} = \pm 20\text{V}$	-	-	± 100	nA
VGS(th)	Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = 250\text{mA}$	1.0	1.4	2.5	V
RDS(ON)	Static Drain-Source ON-Resistance ⁽⁴⁾	$V_{GS} = 10\text{V}$, $I_D = 4\text{A}$	-	29	38	mW
		$V_{GS} = 4.5\text{V}$, $I_D = 3\text{A}$	-	39	65	mW
R _g	Gate Resistance	$f = 1\text{MHz}$	-	27	-	W
C _{iss}	Input Capacitance	$V_{GS}=0\text{V}$, $V_{DS} = 15\text{V}$, $f=1\text{MHz}$	-	243	-	pF
C _{oss}	Output Capacitance		-	40	-	pF
C _{rss}	Reverse Transfer Capacitance		-	31	-	pF
Q _g	Total Gate Charge	$V_{GS} = 0$ to 4.5V $V_{DS} = 15\text{V}$, $I_D = 3\text{A}$	-	6	-	nC
Q _{gs}	Gate Source Charge		-	1	-	nC
Q _{gd}	Gate Drain("Miller") Charge		-	1	-	nC
td(on)	Turn-On DelayTime	$V_{GS} = 10\text{V}$, $V_{DD} = 15\text{V}$ $I_D = 3\text{A}$, $R_{GEN} = 2.7\text{W}$	-	2	-	ns
t _r	Turn-On Rise Time		-	6	-	ns
td(off)	Turn-Off DelayTime		-	24	-	ns
t _f	Turn-Off Fall Time		-	14	-	ns
IS	Maximum Continuous Body Diode Forward Current		-	-	4	A
ISM	Maximum Pulsed Body Diode Forward Current		-	-	15	A
VSD	Body Diode Forward Voltage	$V_{GS} = 0\text{V}$, $I_S = 4\text{A}$	-		1.2	V
trr	Body Diode Reverse Recovery Time	$I_F = 3\text{A}$, $di/dt = 100\text{A/us}$	-	5	-	ns
Qrr	Body Diode Reverse Recovery Charge		-	1.5	-	nC

Note :

- 1、 The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- 2、 The data tested by pulsed , pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$
- 3、 The power dissipation is limited by 150 $^{\circ}\text{C}$ junction temperature
- 4、 The data is theoretically the same as I_D and I_{DM} , in real applications , should be limited by total power dissipation.

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Typical Characteristics

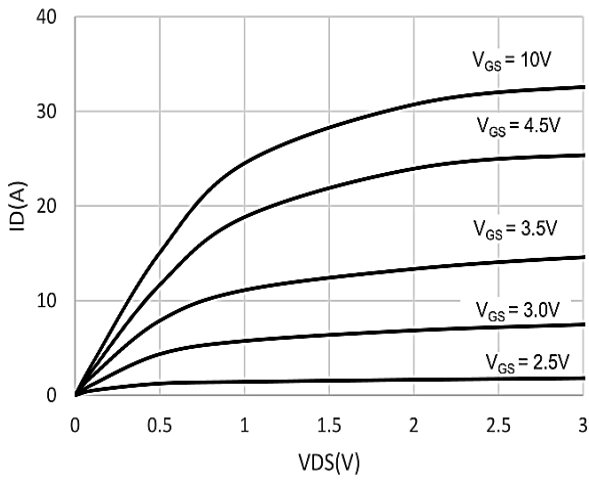


Figure 1: Output Characteristics

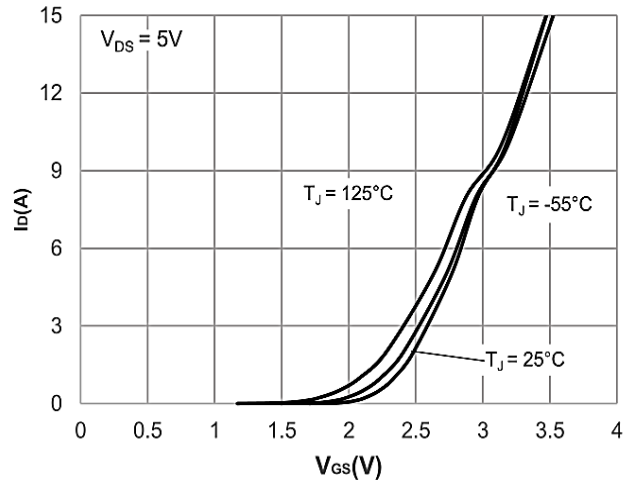


Figure 2: Typical Transfer Characteristics

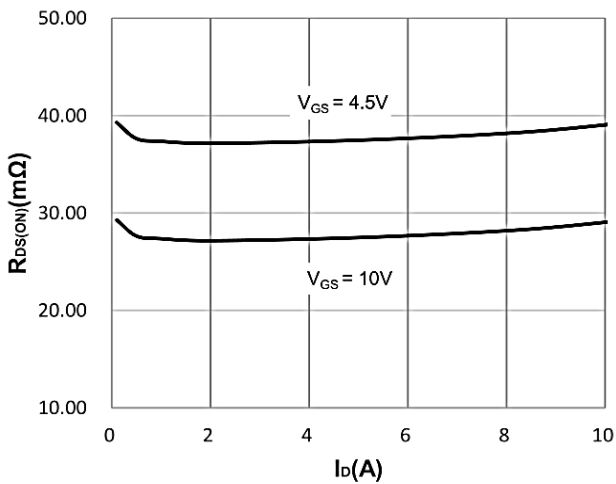


Figure 3: On-resistance vs. Drain Current

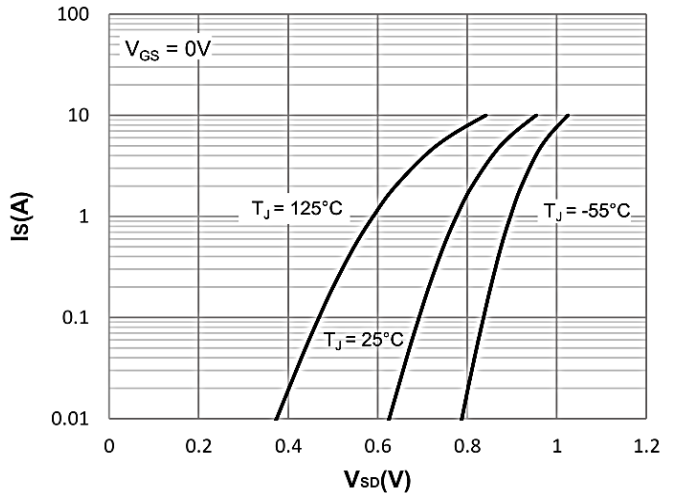


Figure 4: Body Diode Characteristics

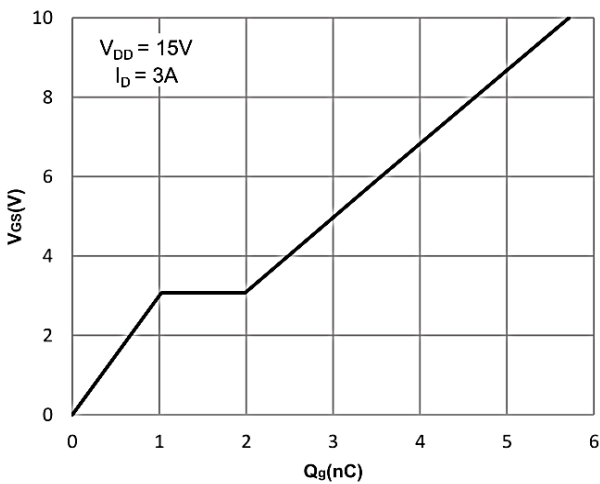


Figure 5: Gate Charge Characteristics

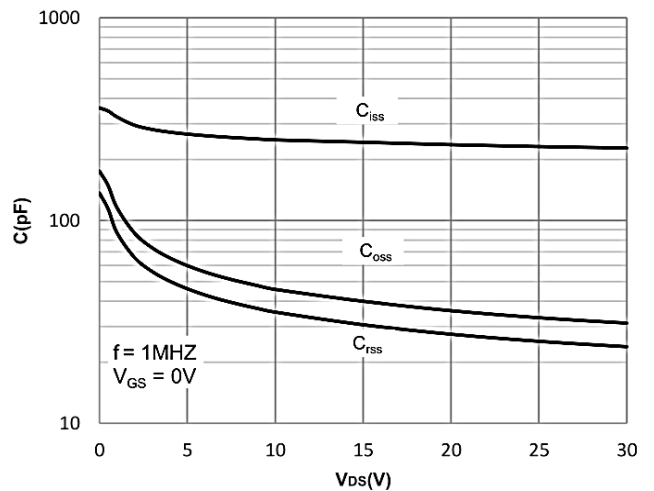


Figure 6: Capacitance Characteristics



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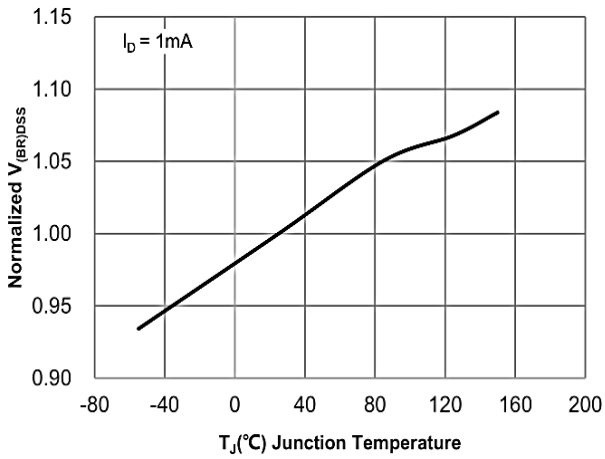


Figure 7: Normalized Breakdown voltage vs. Junction Temperature

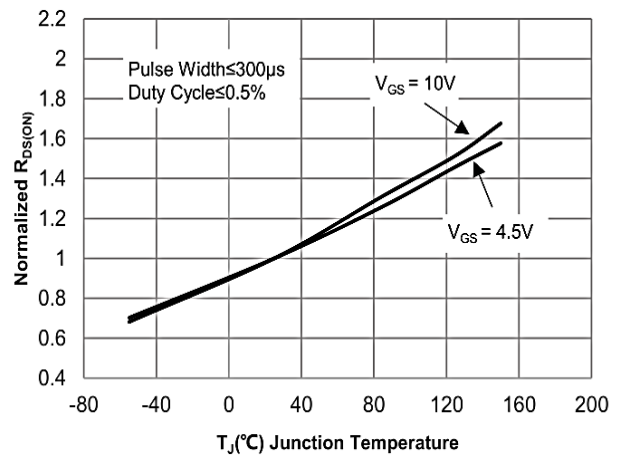


Figure 8: Normalized on Resistance vs. Junction Temperature

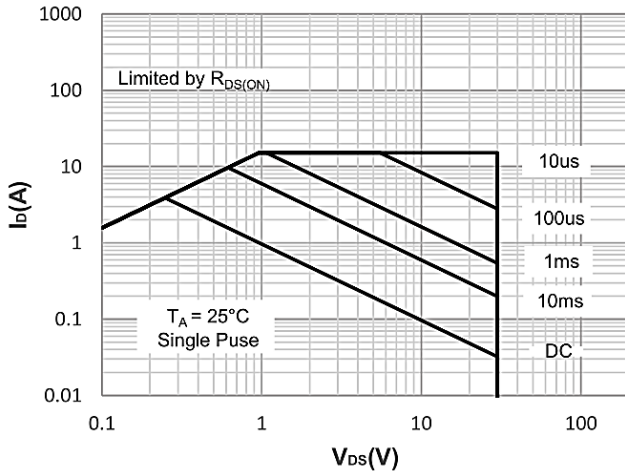


Figure 9: Maximum Safe Operating Area

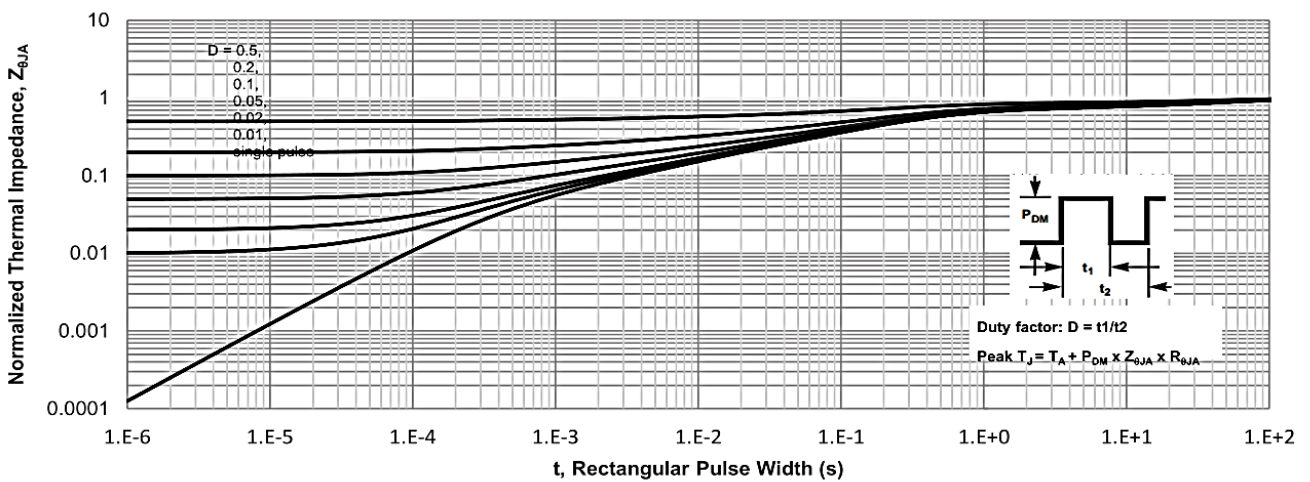
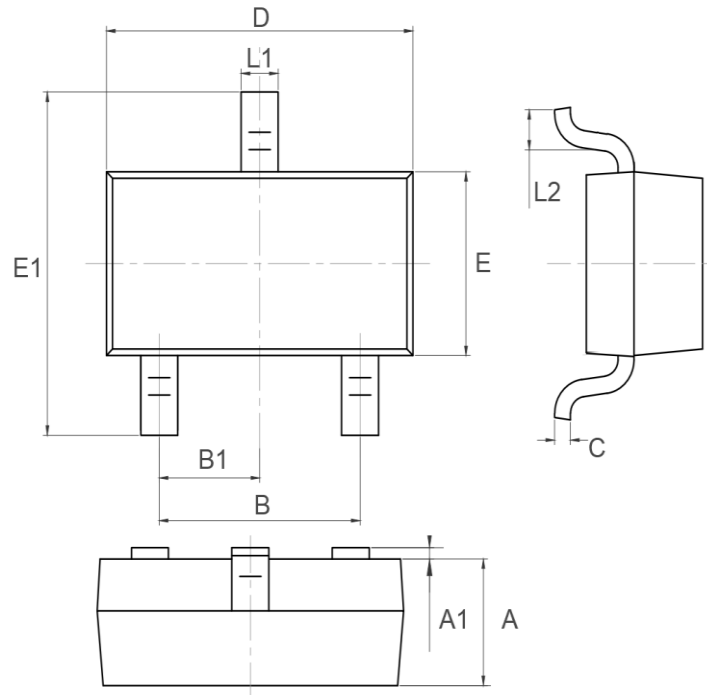


Figure 10: Normalized Maximum Transient Thermal Impedance

Package Mechanical Data-SOT23L-Single



Symbol	Dim in mm		
	Min	Typ	Max
A	0.9	1	1.1
A1	0	0.05	0.1
B	1.8	1.9	2
B1	0.95TYP		
C	0.08	0.115	0.15
D	2.8	2.9	3
E	1.2	1.3	1.4
E1	2.25	2.4	2.55
L1	0.3	0.4	0.5
L2	0.2	0.35	0.5

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Edition	Date	Change
REV1.0	2024/2/1	Initial release

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